**Qualification Results Summary of REF43 Standard Space Level Change of Wafer Diameter and Fab Site**

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| **QUALIFICATION PLAN/STATUS** | | | |
| **TEST** | **SPECIFICATION** | **SAMPLE SIZE** | **RESULTS** |
| Total Ionizing Dose  RHA Level = 30, 50, & 100  K Rads (Si) | MIL-STD-883, Test Method 1019, Condition A  (High Dose Rate) | 32 | 30K Rads – pass  50 K Rads – pass  100 K Rads – pass |
| High Temperature Operating Life Test | MIL-STD-883,  Test Method 1015 | 45(0)  Per wafer lot | In-process, Expected Completion Date November, 2015. |